

Search Notes

Application/Control No.

10/526,758

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

OOYA ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR